



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Wallace T.Y. Tang

Art Unit : 1763

Serial No. : 09/909,766

Examiner : Sylvia R. MacArthur

Filed : July 19, 2001

Title : IN-SITU REAL-TIME MONITORING TECHNIQUE AND APPARATUS FOR  
ENDPOINT DETECTION OF THIN FILMS DURING  
CHEMICAL/MECHANICAL POLISHING PLANARIZATION

MAIL STOP RCE

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449.

This filing is being made with the filing of a Request for Continued Examination. No fee is believed to be due. If, however, there are any charges or credits, please apply them to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 4/8/04

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

April 8, 2004  
Date of Deposit  
Carlos A. Brasil  
Signature

Carlos A. Brasil  
Typed or Printed Name of Person Signing Certificate

Substitute Form PTO-1449 (Modified) <b>Information Disclosure Statement          by Applicant</b> (Use several sheets if necessary) APR 12 2004 (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. <b>05542-459005</b>	Application No. <b>09/909,766</b>
	Applicant <b>Wallace T.Y. Tang</b>		
	Filing Date <b>July 19, 2001</b>	Group Art Unit <b>1763</b>	

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	JP 64-2313	01/1989	JPO			English Equivalent <b>EP 0296680 A1</b>	
	AM	JP 2-86128	07/1990	JPO			Partial Translation	
	AN	JP 60-79304	05/1985	JPO			Partial Translation	
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.